

200 Volt, 0.80Ω HEXFET

HEXFET technology is the key to International Rectifier's advanced line of power MOSFET transistors. The efficient geometry achieves very low on-state resistance combined with high transconductance.

HEXFET transistors also feature all of the well-established advantages of MOSFETs, such as voltage control, very fast switching, ease of paralleling and electrical parameter temperature stability. They are well-suited for applications such as switching power supplies, motor controls, inverters, choppers, audio amplifiers, and high energy pulse circuits, and virtually any application where high reliability is required.

Product Summary

| Part Number | BV _{DSS} | R _{Ds(on)} | I _D |
|--------------|-------------------|---------------------|----------------|
| JANTX2N6790 | 200V | 0.80Ω | 3.5A |
| JANTXV2N6790 | | | |

Features:

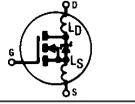
- Avalanche Energy Rating
- Dynamic dv/dt Rating
- Simple Drive Requirements
- Ease of Paralleling
- Hermetically Sealed

Absolute Maximum Ratings

| | Parameter | JANTX2N6790, JANTXV2N6790 | Units |
|--|-----------------------------|--|-------|
| I _D @ V _{GS} = 10V, T _C = 25°C | Continuous Drain Current | 3.5 | A |
| I _D @ V _{GS} = 10V, T _C = 100°C | Continuous Drain Current | 2.25 | |
| I _{DM} | Pulsed Drain Current ① | 14 | |
| P _D @ T _C = 25°C | Max. Power Dissipation | 20 | W |
| | Linear Derating Factor | 0.16 | W/K ⑤ |
| V _{GS} | Gate-to-Source Voltage | ±20 | V |
| dv/dt | Peak Diode Recovery dv/dt ③ | 5.0 | V/ns |
| T _J | Operating Junction | -55 to 150 | °C |
| T _{STG} | Storage Temperature Range | | |
| | Lead Temperature | 300 (0.063 in. (1.6mm) from case for 10.5 seconds) | |
| | Weight | 0.98 (typical) | g |

JANTX2N6790, JANTXV2N6790 Device

Electrical Characteristics @ T_j = 25°C (Unless Otherwise Specified)

| | Parameter | Min. | Typ. | Max. | Units | Test Conditions |
|-------------------------------------|--|------|------|------|-------|--|
| BV _{DSS} | Drain-to-Source Breakdown Voltage | 200 | — | — | V | V _{GS} = 0V, I _D = 1.0 mA |
| ΔBV _{DSS} /ΔT _J | Temperature Coefficient of Breakdown Voltage | — | 0.25 | — | V/°C | Reference to 25°C, I _D = 1.0 mA |
| RDS(on) | Static Drain-to-Source | — | — | 0.80 | Ω | V _{GS} = 10V, I _D = 2.25A ^④ |
| | On-State Resistance | — | — | 0.92 | | V _{GS} = 10V, I _D = 3.5A |
| VGS(th) | Gate Threshold Voltage | 2.0 | — | 4.0 | V | V _{DS} = V _{GS} , I _D = 250μA |
| g _{fs} | Forward Transconductance | 1.5 | — | — | S (r) | V _{DS} > 15V, I _{DS} = 2.25A ^④ |
| IDSS | Zero Gate Voltage Drain Current | — | — | 25 | μA | V _{DS} = 0.8 x Max Rating, V _{GS} = 0V |
| | | — | — | 250 | | V _{DS} = 0.8 x Max Rating V _{GS} = 0V, T _J = 125°C |
| IGSS | Gate-to-Source Leakage Forward | — | — | 100 | nA | V _{GS} = 20V |
| IGSS | Gate-to-Source Leakage Reverse | — | — | -100 | nA | V _{GS} = -20V |
| Q _g | Total Gate Charge | 8.0 | — | 14.3 | nC | V _{GS} = 10V, I _D = 3.5A |
| Q _{gs} | Gate-to-Source Charge | 0.9 | — | 3.0 | | V _{DS} = Max. Rating x 0.5 |
| Q _{gd} | Gate-to-Drain ("Miller") Charge | 2.3 | — | 9.0 | | see figures 6 and 13 |
| t _{d(on)} | Turn-On Delay Time | — | — | 40 | ns | V _{DD} = 100V, I _D = 3.5A, R _G = 7.5Ω, V _{GS} = 10V |
| t _r | Rise Time | — | — | 50 | | |
| t _{d(off)} | Turn-Off Delay Time | — | — | 50 | | |
| t _f | Fall Time | — | — | 50 | | |
| LD | Internal Drain Inductance | — | 5.0 | — | nH | <p>Measured from the drain lead, 6mm (0.25 in.) from package to center of die.</p> <p>Modified MOSFET symbol showing the internal inductances.</p>  |
| LS | Internal Source Inductance | — | 15 | — | | |
| C _{iss} | Input Capacitance | — | 260 | — | pF | V _{GS} = 0V, V _{DS} = 25V f = 1.0 MHz see figure 5 |
| C _{oss} | Output Capacitance | — | 100 | — | | |
| C _{rss} | Reverse Transfer Capacitance | — | 30 | — | | |

Source-Drain Diode Ratings and Characteristics

| | Parameter | Min. | Typ. | Max. | Units | Test Conditions |
|-----------------|--|--|------|------|-------|---|
| I _S | Continuous Source Current (Body Diode) | — | — | 3.5 | A | Modified MOSFET symbol showing the integral reverse p-n junction rectifier. |
| I _{SM} | Pulse Source Current (Body Diode) ^① | — | — | 14 | | |
| V _{SD} | Diode Forward Voltage | — | — | 1.5 | V | T _j = 25°C, I _S = 3.5A, V _{GS} = 0V ^④ |
| t _{rr} | Reverse Recovery Time | — | — | 400 | ns | T _j = 25°C, I _F = 3.5A, di/dt ≤ 100A/μs |
| Q _{RR} | Reverse Recovery Charge | — | — | 4.3 | μC | V _{DD} ≤ 50V ^④ |
| t _{on} | Forward Turn-On Time | Intrinsic turn-on time is negligible. Turn-on speed is substantially controlled by L _S + L _D . | | | | |

Thermal Resistance

| | Parameter | Min. | Typ. | Max. | Units | Test Conditions |
|-------------------|---------------------|------|------|------|-------|----------------------|
| R _{thJC} | Junction-to-Case | — | — | 6.25 | K/W | Typical socket mount |
| R _{thJA} | Junction-to-Ambient | — | — | 175 | | |

JANTX2N6790, JANTXV2N6790 Device

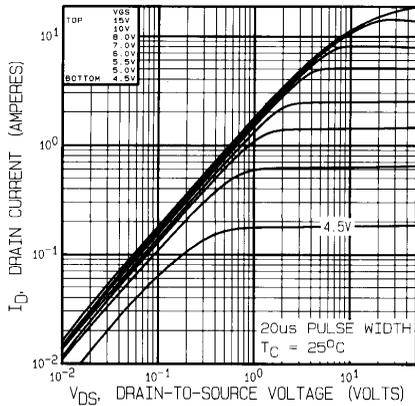


Fig. 1 — Typical Output Characteristics
 $T_C = 25^\circ\text{C}$

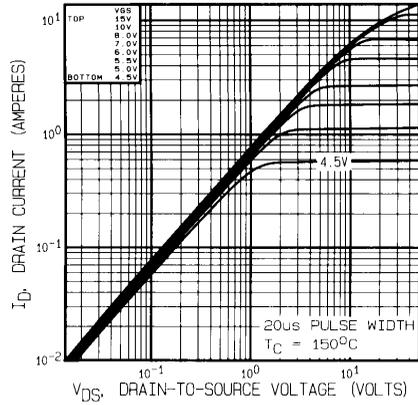


Fig. 2 — Typical Output Characteristics
 $T_C = 150^\circ\text{C}$

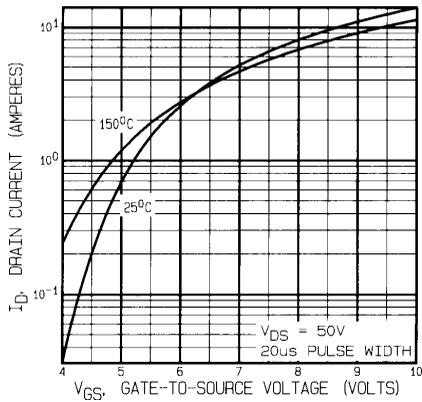


Fig. 3 — Typical Transfer Characteristics

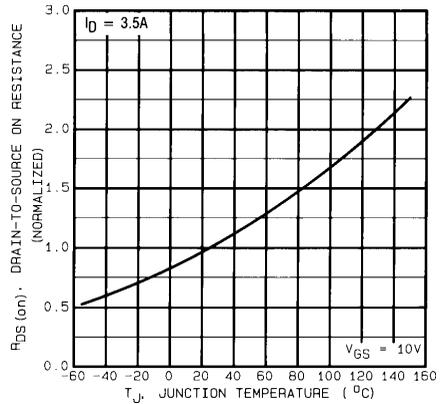


Fig. 4 — Normalized On-Resistance Vs. Temperature

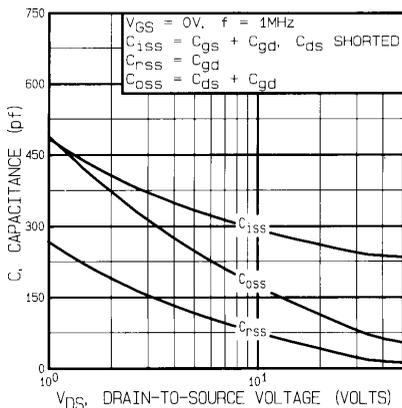


Fig. 5 — Typical Capacitance Vs. Drain-to-Source Voltage

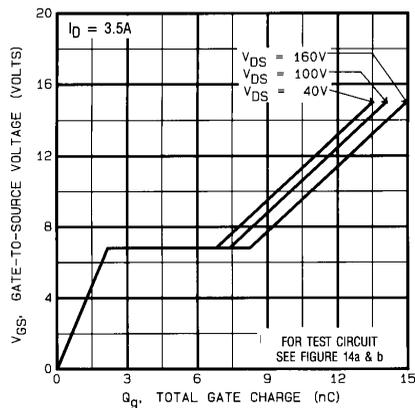


Fig. 6 — Typical Gate Charge Vs. Gate-to-Source Voltage

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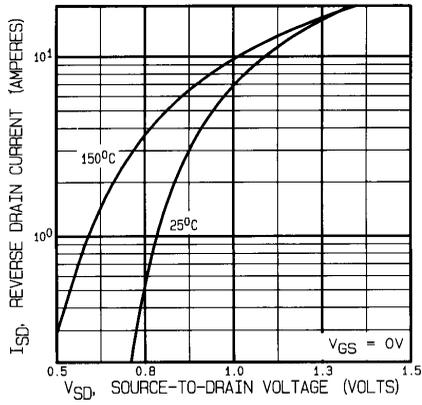


Fig. 7 — Typical Source-to-Drain Diode Forward Voltage

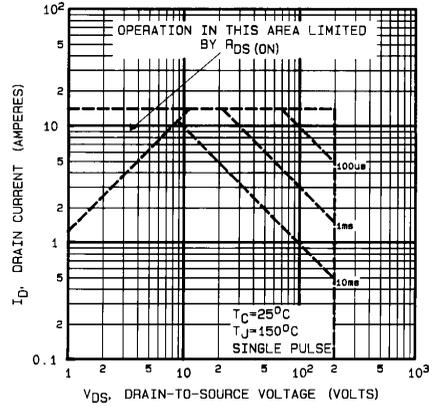


Fig. 8 — Maximum Safe Operating Area

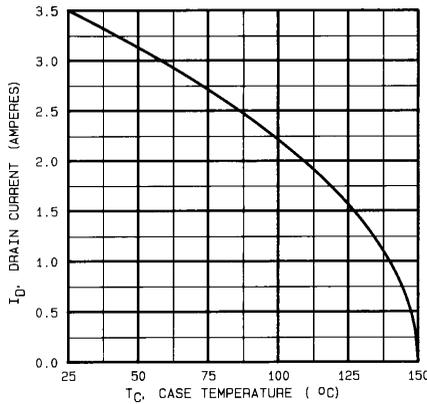


Fig. 9 — Maximum Drain Current Vs. Case Temperature

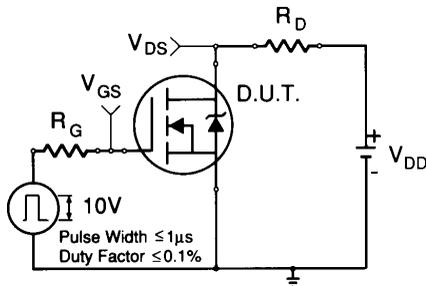


Fig. 10a — Switching Time Test Circuit

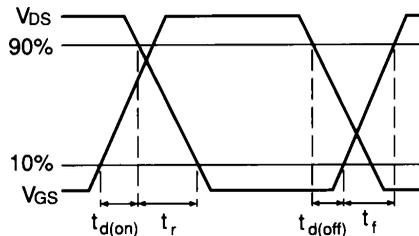


Fig. 10b — Switching Time Waveforms

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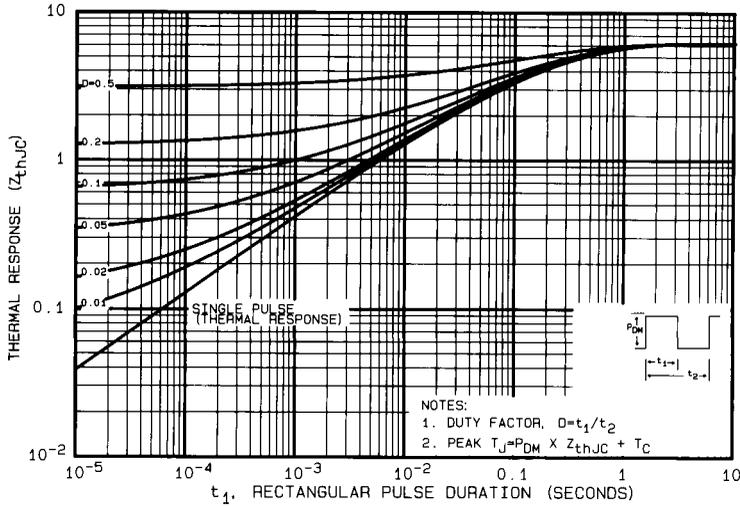


Fig. 11 — Maximum Effective Transient Thermal Impedance, Junction-to-Case Vs. Pulse Duration

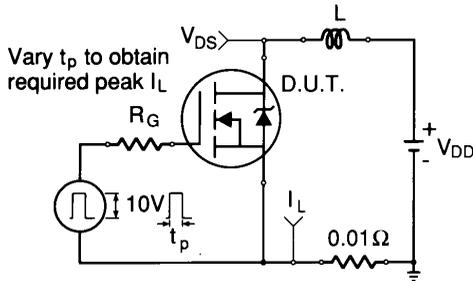


Fig. 12a — Unclamped Inductive Test Circuit

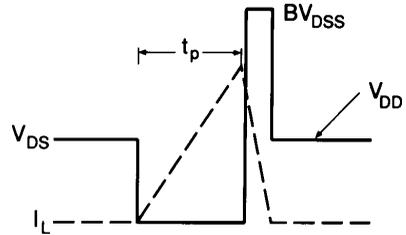


Fig. 12b — Unclamped Inductive Waveforms

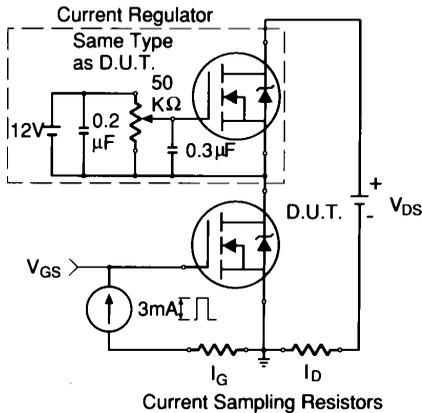


Fig. 13a — Gate Charge Test Circuit

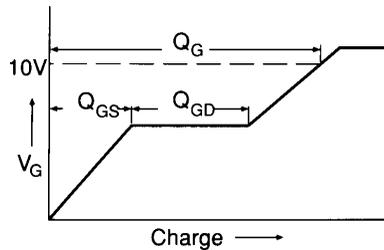
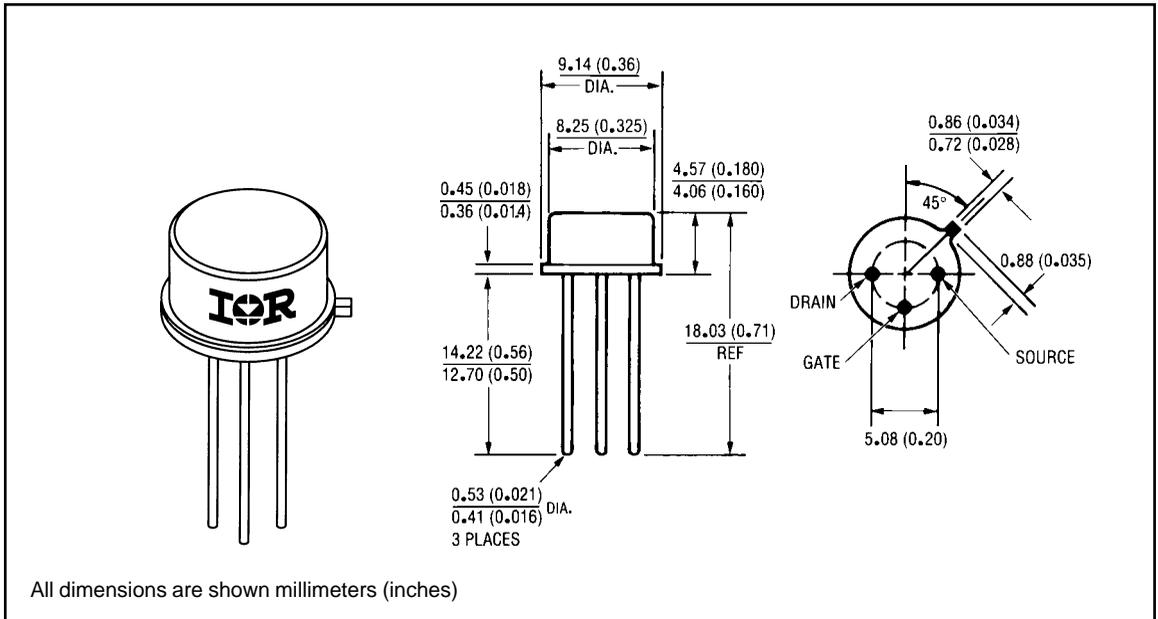


Fig. 13b — Basic Gate Charge Waveform

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- ① Repetitive Rating; Pulse width limited by maximum junction temperature. (see figure 11)
- ② @ $V_{DD} = 50V$, Starting $T_J = 25^\circ C$,
 $E_{AS} = [0.5 * L * (I_L^2) * [BV_{DSS}/(BV_{DSS}-V_{DD})]$
 Peak $I_L = 3.5A$, $V_{GS} = 10V$, $25 \leq R_G \leq 200\Omega$
- ③ $I_{SD} \leq 3.5A$, $di/dt \leq 95A/\mu s$,
 $V_{DD} \leq BV_{DSS}$, $T_J \leq 150^\circ C$
- ④ Pulse width $\leq 300 \mu s$; Duty Cycle $\leq 2\%$
- ⑤ $K/W = ^\circ C/W$
 $W/K = W/^\circ C$

Case Outline and Dimensions — TO-205AF (Modified TO-39)



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Data and specifications subject to change without notice.

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